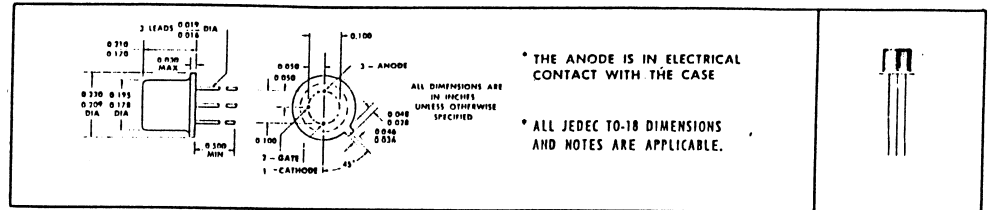


2N3002
 SILICON CONTROLLED SWITCH

mechanical data

The devices are in a hermetically sealed welded case with a glass-to-metal seal between case and leads. Approximate weight is 0.35 grams.



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

		UNIT
*Continuous Forward Blocking Voltage, V_{FB} (See Note 1)	60	v
*Continuous Reverse Blocking Voltage, V_R	60	v
*Peak Forward Blocking Voltage (See Note 1)	60	v
*Peak Reverse Blocking Voltage	60	v
Peak Gate Reverse Voltage	8	v
*Continuous Anode Forward Current at (or below) 55°C Free-Air Temperature (See Note 2)	350	ma
*Continuous Anode Forward Current at 130°C Free-Air Temperature (See Note 2)	75	ma
*Average Anode Forward Current (180° Conduction Angle) at (or below) 55°C Free-Air Temperature (See Note 2)	250	ma
*Anode Surge Current (See Note 3)	6	a
*Peak Gate Forward Current (Pulse width \leq 8 msec)	250	ma
*Average Gate Power Dissipation	100	mw
*Operating Free-Air Temperature Range	-65 to +150	°C
*Storage Temperature Range	-65 to +200	°C

*electrical characteristics at 25°C free-air temperature (unless otherwise noted)

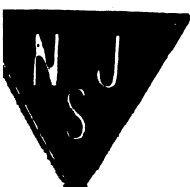
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
I_F Anode Forward Blocking Current†	$V_{AK} = \text{Rated } V_{FB}, R_{GK} = 1 \text{ k}\Omega$			20	ma
	$V_{AK} = \text{Rated } V_{FB}, R_{GK} = 1 \text{ k}\Omega, T_A = 150^\circ\text{C}$			20	μa
I_R Anode Reverse Blocking Current†	$V_{KA} = \text{Rated } V_R, R_{GK} = \infty$			0.1	μa
	$V_{KA} = \text{Rated } V_R, R_{GK} = \infty, T_A = 150^\circ\text{C}$			100	μa
I_{GR} Gate Reverse Current	$V_{KG} = 5 \text{ v}, R_L = \infty$			0.1	μa
$I_{GT(\text{on})}$ Gate Trigger Current†	$V_{AA} = 5 \text{ v}, R_L = 12 \Omega$		5.0	20	μa
$V_{GT(\text{on})}$ Gate Trigger Voltage†	$V_{AA} = 5 \text{ v}, R_L = 12 \Omega, T_A = -65^\circ\text{C}$			0.9	v
	$V_{AA} = 5 \text{ v}, R_L = 12 \Omega$		0.55	0.7	v
	$V_{AA} = 5 \text{ v}, R_L = 12 \Omega, T_A = 150^\circ\text{C}$	0.2			v
I_H Holding Current	$R_{GK} = 1 \text{ k}\Omega$		1.2	3.0	ma
	$R_{GK} = 1 \text{ k}\Omega, T_A = -65^\circ\text{C}$			4.0	ma
V_F Peak Instantaneous Fwd. Voltage	$I_F = 350 \text{ ma}$, (See Note 4)			1.1	v
dV/dt Critical Rate of Anode Voltage Rise	$V_{KG} = 1.0 \text{ v}$		400		v/ μsec

NOTES: 1. This value applies when the Gate-Cathode Resistance, $R_{GK} \leq 1 \text{ k}\Omega$

2. For operation above 55°C free-air temperature, refer to Anode Forward Current Derating Curve, Figure 1.

3. This rating applies for one half-cycle sine wave, 60 cps, when the device is conducting maximum rated current immediately before and after the surge. Surge may be repeated after the device has returned to original thermal equilibrium conditions.

*Indicates JEDEC registered data.



*ELECTRICAL CHARACTERISTICS (I_A = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
Collector Cutoff Current (V _{CB} = 50 Vdc, I _E = 0) (V _{CB} = 50 Vdc, I _E = 0, T _A = 150°C)	I _{CBO}	---	0.025 15	μ A dc
Collector Cutoff Current (V _{CE} = 30 Vdc, V _{BE} = 0.5 Vdc)	I _{CEX}	---	.050	μ A dc
Base Cutoff Current (V _{CE} = 30 Vdc, V _{BE} = 0.5 Vdc)	I _{BL}	---	.050	μ A dc
Collector-Base Breakdown Voltage (I _C = 10 μ A dc, I _E = 0)	BV _{CBO}	60	---	Vdc
Collector-Emitter Breakdown Voltage ⁽¹⁾ (I _C = 10 mA dc, pulsed, I _B = 0)	BV _{CEO}	20	---	Vdc
Emitter-Base Breakdown Voltage (I _E = 10 μ A dc, I _C = 0)	BV _{EBO}	5.0	---	Vdc
Collector Saturation Voltage ⁽¹⁾ (I _C = 150 mA dc, I _B = 15 mA dc)	V _{CE (sat)}	---	0.5	Vdc
Base-Emitter Saturation Voltage ⁽¹⁾ (I _C = 150 mA dc, I _B = 15 mA dc)	V _{BE (sat)}	---	1.3	Vdc
DC Forward Current Transfer Ratio (I _C = 150 mA dc, V _{CE} = 10 Vdc)	h _{FE}	100	300	---
Common-Base Open Circuit Output Capacitance (V _{CB} = 10 V, I _E = 0, f = 100 kHz)	C _{ob}	---	8.0	pF
Delay Time (V _{CC} = 30 V, I _{CS} = 150 mA, I _{B1} = 15 mA)	t _d	---	20	ns
Rise Time (V _{CC} = 30 V, I _{CS} = 150 mA, I _{B1} = 15 mA)	t _r	---	75	ns
Storage Time (V _{CC} = 6 V, I _{CS} = 150 mA, I _{B1} = 15 mA, I _{B2} = 15 mA)	t _s	---	300	ns
Fall Time (V _{CC} = 6 V, I _{CS} = 150 mA, I _{B1} = 15 mA, I _{B2} = 15 mA)	t _f	---	200	ns
Current Gain-Bandwidth Product (I _C = 20 mA, V _{CE} = 20 V, f = 100 MHz)	f _T	250	---	MHz

⁽¹⁾ PULSE TEST: Pulse width ≤ 300 μs, duty cycle ≤ 2%

*Indicates JEDEC Registered Data